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LOG OF MEETING DIRECTORATE FOR ENGINEERING SCIENCES

SUBJECT: Meeting of the Industry Advisory Group of UL for Plastic Materials

DATE(S) OF MEETING: May 2, 2001

PLACE: Best Western – Lake Buena Vista Resort Hotel, Lake Buena Vista, FL

LOG ENTRY SOURCE: Hammad A. Malik, PE *HAM*

DATE OF ENTRY: May 8, 2001

COMMISSION ATTENDEES:
Hammad A. Malik, PE, ESEE

NON-COMMISSION ATTENDEES:
See Attached Attendee List

SUMMARY OF MEETING:

Mr. George Fechtmann, UL, started by having all attendees introduce themselves and providing introductory remarks.

Mr. Steve Giannoni, UL, and Mr. Fechtmann provided an update on harmonization of UL plastics requirements with international standards.

Ms. Debbie Oates, UL, provided on an information on efforts to combine various UL inspections, audits, and other visits that UL is required to make to their client sites.

Mr. Giannoni indicated that information relating to polymer variations that is currently available on the net is being formatted to be included in the affected UL standards. This information was developed to help product designers with determining acceptable polymer substitutions in order to minimize or eliminate new plastics testing.

Ms. Oates advised of the plan to include additional information on the Plastics Recognition Cards to help product designers in materials selection.

Ms. Tiffany Eldred, UL, provided a demonstration of the UL IQ for Plastics application that is currently available on UL's website. This application provides designers, plastics manufacturers, and others with reliable pre-selection information.

Mr. Giannoni provided an update on UL's examination of thermal aging requirements of plastics and provided information on a new procedure for measuring thermal aging characteristics. The formation of a new Ad-Hoc group was announced. The purpose of this group is to develop a thermal aging consistency procedure guide.

Ms. Crystal Vanderpan, UL, provided information regarding an examination of the reuse of plastics. The formation of an Ad-Hoc group for this purpose was announced.

Ms. Ray Wilkerson, UL, provided information on sample thickness requirements flammability tests of plastic materials.

Mr. Fechtmann provided a summary of the new "alternative paths" when determining flammability requirements for plastics usage in electrical appliances. It was also announced that a revised standard and adoption bulletin will be issued by the end of this May.

Mr. Giannoni discussed plastics issues relating to 42V automotive battery applications. The plan to "fix-up" contradictions and inconsistencies in generic plastic requirements was announced.

Mr. Fechtmann indicated that an insulating systems database has been developed. This relational database was designed to help product designers in selecting what materials can be used in electrical insulating systems within appliances.

Ms. Oates briefed the group on plans to eliminate redundant UL product categories.

MAY 2001 PLASTICS IAG MEETING IN ORLANDO, FL
ATTENDANCE COPY - PLEASE SIGN AND PASS ALONG TO OTHERS

NAME	COMPANY	IAG or GUEST	WILL ATTEND ?	E-MAIL ADDRESS
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5/1/01

If you are at the meeting but not represented on the above list, please sign in below:
